

WHAT WE CLAIM IS:

1. A scanning electron microscope comprising an electron source, a lens for condensing the primary electron beam which is emitted from said electrode, a detector for detecting electrons which are generated by radiation of the primary electron beam condensed by said lens onto a specimen, a first decelerating means for decelerating the primary electron beam to be hit against said specimen, a second decelerating means for decelerating the electrons which are generated from said specimen, and a deflector for deflecting the electrons which are decelerated by said second decelerating means towards said detector.